## D J Wallis

## List of Publications by Year in descending order

Source: https://exaly.com/author-pdf/11744767/publications.pdf

Version: 2024-02-01

623734 477307 33 854 14 29 h-index citations g-index papers 33 33 33 1168 all docs docs citations times ranked citing authors

#	Article	IF	CITATIONS
1	Prospects of III-nitride optoelectronics grown on Si. Reports on Progress in Physics, 2013, 76, 106501.	20.1	249
2	Time-Resolved Temperature Measurement of AlGaN/GaN Electronic Devices Using Micro-Raman Spectroscopy. IEEE Electron Device Letters, 2007, 28, 86-89.	3.9	114
3	Heterogeneous integration of gallium nitride light-emitting diodes on diamond and silica by transfer printing. Optics Express, 2015, 23, 9329.	3.4	57
4	GaN-based LEDs grown on 6-inch diameter Si (111) substrates by MOVPE. Proceedings of SPIE, 2009, , .	0.8	41
5	High-mobility two-dimensional electron gases in Si/SiGe heterostructures on relaxed SiGe layers grown at high temperature. Semiconductor Science and Technology, 1997, 12, 943-946.	2.0	36
6	Thermal mapping of defects in AlGaNâ^•GaN heterostructure field-effect transistors using micro-Raman spectroscopy. Applied Physics Letters, 2005, 87, 103508.	3.3	34
7	Analysis of thin AlN carrier exclusion layers in AlGaN/GaN microwave heterojunction field-effect transistors. Semiconductor Science and Technology, 2004, 19, L65-L67.	2.0	28
8	On the incorporation mechanism of Fe in GaN grown by metal-organic vapour phase epitaxy. Physica Status Solidi C: Current Topics in Solid State Physics, 2006, 3, 1429-1434.	0.8	26
9	High Performance GaN High Electron Mobility Transistors on Low Resistivity Silicon for & lt;inline-formula> & lt;tex-math notation="LaTeX">\$X\$ & lt;/tex-math>-Band Applications. IEEE Electron Device Letters, 2015, 36, 899-901.	3.9	25
10	Control of Short-Channel Effects in GaN/AlGaN HFETs. , 2006, , .		24
11	AlGaN/GaN microwave HFET including a thin AlN carrier exclusion layer. Physica Status Solidi C: Current Topics in Solid State Physics, 2003, 0, 2331-2334.	0.8	23
12	Measuring the composition of AlGaN layers in GaN based structures grown on 150 mm Si substrates using (2 0 5) reciprocal space maps. Semiconductor Science and Technology, 2013, 28, 094006.	2.0	23
13	Analysis of nanometre-sized pyrogenic particles in the scanning transmission electron microscope. Journal of Microscopy, 1996, 184, 185-194.	1.8	18
14	Photoluminescence studies of cubic GaN epilayers. Physica Status Solidi (B): Basic Research, 2017, 254, 1600733.	1.5	16
15	Origin of kink effect in AlGaN/GaN high electron mobility transistors: Yellow luminescence and Fe doping. Applied Physics Letters, 2012, 101, .	3.3	15
16	Composition measurement in strained AlGaN epitaxial layers using x-ray diffraction. Applied Physics Letters, 2004, 85, 6359-6361.	3.3	12
17	Novel Shielded Coplanar Waveguides on GaN-on-Low Resistivity Si Substrates for MMIC Applications. IEEE Microwave and Wireless Components Letters, 2015, 25, 427-429.	3.2	12
18	InGaN µLEDs integrated onto colloidal quantum dot functionalized ultra-thin glass. Optics Express, 2017, 25, 19179.	3.4	12

#	Article	IF	Citations
19	High-Performance MMIC Inductors for GaN-on-Low-Resistivity Silicon for Microwave Applications. IEEE Microwave and Wireless Components Letters, 2018, 28, 99-101.	3.2	10
20	Effect of stacking faults on the photoluminescence spectrum of zincblende GaN. Journal of Applied Physics, $2018,123,.$	2.5	10
21	Terahertz monolithic integrated circuits (TMICs) array antenna technology on GaN-on-Low resistivity silicon substrates., 2016,,.		9
22	Photoluminescence efficiency of zincblende InGaN/GaN quantum wells. Journal of Applied Physics, 2021, 129, .	2.5	9
23	Low-Loss MMICs Viable Transmission Media for GaN-on-Low Resistivity Silicon Technology. IEEE Microwave and Wireless Components Letters, 2017, 27, 10-12.	3.2	8
24	Alloy segregation at stacking faults in zincblende GaN heterostructures. Journal of Applied Physics, 2020, 128, 145703.	2.5	8
25	Z-contrast imaging of AlN exclusion layers in GaN field-effect transistors. Applied Physics Letters, 2005, 87, 042101.	3.3	7
26	Method for inferring the mechanical strain of GaN-on-Si epitaxial layers using optical profilometry and finite element analysis. Optical Materials Express, 2021, 11, 1643.	3.0	7
27	Stacking fault-associated polarized surface-emitted photoluminescence from zincblende $InGaN/GaN$ quantum wells. Applied Physics Letters, 2020, 117, .	3.3	6
28	Synthesis and Properties of GaAs Nanocrystals in Sio2 Formed by Ion Implantation. Materials Research Society Symposia Proceedings, 1995, 396, 447.	0.1	4
29	Mosaic Crystal Tilts and Their Relationship to Dislocation Structure, Surface Roughness and Growth Conditions in Relaxed SiGe Layers. Materials Research Society Symposia Proceedings, 1998, 533, 77.	0.1	4
30	The effect of thermal annealing on the optical properties of Mg-doped zincblende GaN epilayers. Journal of Applied Physics, 2021, 130, .	2.5	3
31	Time-resolved nanosecond sub-micron resolution thermal analysis of high-power AlGaN/GaN HFETs. Physica Status Solidi (A) Applications and Materials Science, 2007, 204, 2014-2018.	1.8	2
32	Integrated dual-color InGaN light-emitting diode array through transfer printing. , 2015, , .		2
33	A Combined-Techniques Approach to Elucidating Crystalline Interface Atomic Structure. Materials Research Society Symposia Proceedings, 1996, 466, 45.	0.1	0